

# AON3810 20V Dual N-Channel MOSFET

## **General Description**

The AON3810 uses advanced trench technology to provide excellent  $R_{\rm DS(ON)},$  low gate charge and operation with gate voltages as low as 1.8V while retaining a 12V  $V_{\rm GS(MAX)}$  rating. It is ESD protected. This device is suitable for use as a uni-directional or bi-directional load switch, facilitated by its commondrain configuration.

## **Product Summary**

 $V_{DS}(V) = 20V$ 

 $I_D = 8.5A (V_{GS} = 10V)$ 

 $R_{DS(ON)}$  < 24m $\Omega$  ( $V_{GS}$  = 10V)

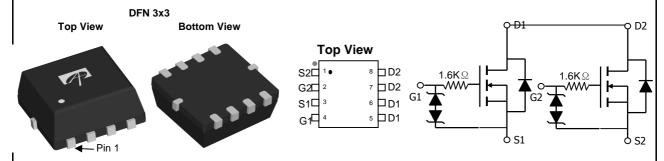
 $R_{\text{DS(ON)}} < 28 \text{m}\Omega \; (\text{V}_{\text{GS}} = 4.5 \text{V})$ 

 $R_{\text{DS(ON)}} < 39 \text{m}\Omega \; (\text{V}_{\text{GS}} = 2.5 \text{V})$ 

 $R_{\text{DS(ON)}} < 55 \text{m}\Omega \; (\text{V}_{\text{GS}} = 1.8 \text{V})$ 

ESD Rating: 2000V HBM





Absolute Maximum Ratings T <sub>A</sub> =25℃ unless otherwise noted									
Parameter		Symbol	Maximum	Units					
Drain-Source Voltage		$V_{DS}$	20	V					
Gate-Source Voltage		$V_{GS}$	±12	V					
Continuous Drain	T <sub>A</sub> =25℃		8.5						
Current <sup>A</sup>	T <sub>A</sub> =70℃	$I_D$	6.8	А					
Pulsed Drain Current <sup>B</sup>		I <sub>DM</sub>	30						
	T <sub>A</sub> =25℃	D	2.5	W					
Power Dissipation <sup>A</sup>	T <sub>A</sub> =70℃	$P_{D}$	1.6	VV					
Junction and Storage Temperature Range		$T_J, T_{STG}$	-55 to 150	C					

Thermal Characteristics								
Parameter	Symbol	Тур	Max	Units				
Maximum Junction-to-Ambient A	t ≤ 10s		40	50	€\M			
Maximum Junction-to-Ambient A	Steady-State R <sub>θJA</sub>		75	95	°C/W			
Maximum Junction-to-Lead <sup>C</sup>	Steady-State	$R_{ heta JL}$	30	40	℃/W			

### Electrical Characteristics (T<sub>J</sub>=25℃ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Тур	Max	Units
STATIC F	PARAMETERS					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	20			V
I <sub>DSS</sub>	Zoro Coto Voltago Proin Current	$V_{DS}$ =16V, $V_{GS}$ =0V			1	
	Zero Gate Voltage Drain Current	T <sub>J</sub> =55℃			5	μΑ
$I_{GSS}$	Gate-Body leakage current	$V_{DS}$ =0V, $V_{GS}$ =±10V			10	
$BV_{GSO}$	Gate-Source Breakdown Voltage	$V_{DS}$ =0V, $I_{G}$ =±250uA	±12			V
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ $I_{D}=250uA$	0.5	0.7	1	V
$I_{D(ON)}$	On state drain current	$V_{GS}$ =4.5V, $V_{DS}$ =5V	30			Α
		$V_{GS}$ =10V, $I_D$ =7A	16	20	24	mΩ
		T <sub>J</sub> =125℃	22	28	35	
	Static Drain-Source On-Resistance	$V_{GS}$ =4.5V, $I_{D}$ =6A	19	24	29	mΩ
		$V_{GS}$ =2.5V, $I_D$ =5A	25	32	39	mΩ
		$V_{GS}$ =1.8V, $I_D$ =2A	35	46	55	mΩ
<b>g</b> <sub>FS</sub>	Forward Transconductance	$V_{DS}=5V$ , $I_{D}=7A$		21		S
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =1A,V <sub>GS</sub> =0V		0.66	1	V
Is	Maximum Body-Diode Continuous Current				2.5	Α
DYNAMIC	PARAMETERS					
C <sub>iss</sub>	Input Capacitance			280		pF
Coss	Output Capacitance	$V_{GS}$ =0V, $V_{DS}$ =10V, f=1MHz		105		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			35		pF
$R_g$	Gate resistance	$V_{GS}$ =0V, $V_{DS}$ =0V, f=1MHz		1.6		kΩ
SWITCHI	NG PARAMETERS					
$Q_g$	Total Gate Charge			5.2		nC
$Q_{gs}$	Gate Source Charge	$V_{GS}$ =4.5V, $V_{DS}$ =10V, $I_{D}$ =7A		2.1		nC
$Q_{gd}$	Gate Drain Charge			1.9		nC
t <sub>D(on)</sub>	Turn-On DelayTime			280		ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ =4.5V, $V_{DS}$ =10V, $R_L$ =1.5 $\Omega$ ,		972		ns
$t_{D(off)}$	Turn-Off DelayTime	$R_{GEN}=3\Omega$		2.35		μs
t <sub>f</sub>	Turn-Off Fall Time			2.2		μs
t <sub>rr</sub>	Body Diode Reverse Recovery Time	$I_F=7A$ , $dI/dt=100A/\mu s$ , $V_{GS}=-9V$		25		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	ge I <sub>F</sub> =7A, dl/dt=100A/μs, V <sub>GS</sub> =-9V		8		nC

A: The value of R  $_{\theta JA}$  is measured with the device mounted on 1in  $^2$  FR-4 board with 2oz. Copper, in a still air environment with T  $_A$  =25°C. The value in any given application depends on the user's specific board design. The currentand power rating is based on the t  $\leq$  10s thermal resistance rating.

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B: Repetitive rating, pulse width limited by junction temperature.

C. The R  $_{\theta JA}$  is the sum of the thermal impedence from junction to lead R  $_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using <300  $\mu s$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in <sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T <sub>A</sub>=25°C. The SOA curve provides a single pulse rating.

Rev 3: Nov. 2010

### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

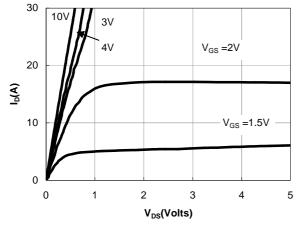


Figure 1: On-Regions CharacteristiCS

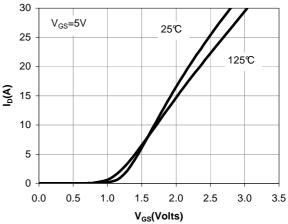


Figure 2: Transfer Characteristics

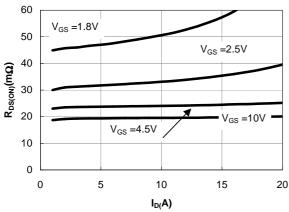


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

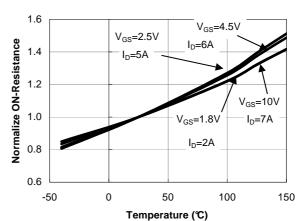


Figure 4: On-Resistance vs. Junction Temperature

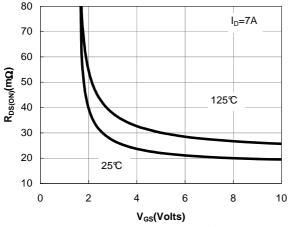


Figure 5: On-Resistance vs. Gate-Source Voltage

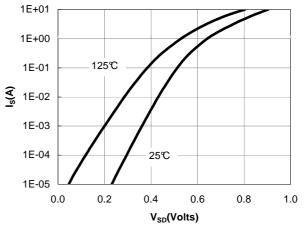
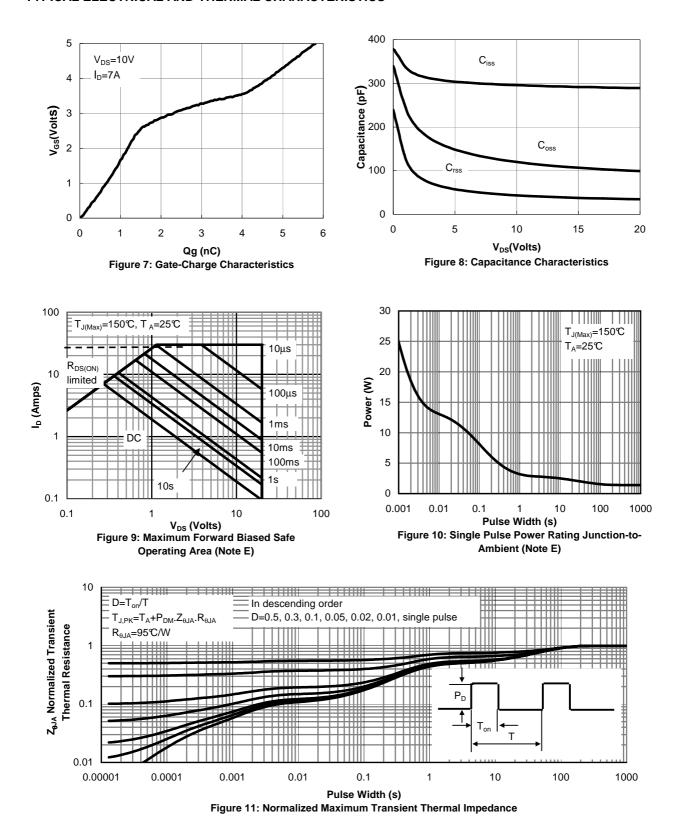


Figure 6: Body-Diode Characteristics

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Alpha & Omega Semiconductor, Ltd.